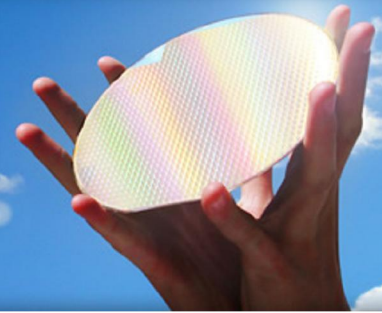




## Cutting the cost of analog test



V1.8

## LinBIST for ADCs: Audio, Video and more...

### Simplified Test Access

Chips are becoming so crowded they are nearly impossible to test, especially with the rise of System-on-Chip and System-in-Package products.

LinBIST removes the need to provide test access for each analog block, saving pins and avoiding the need for complicated test multiplexers.

### Reduced Test Cost

Analog Test Equipment is expensive, and has limited capacity for testing more than one die simultaneously.

LinBIST allows analog System-on-Chip blocks to be tested in parallel on low-cost digital test equipment, resulting in up to 90% saving in test costs.

## Easy to Implement



The LinBIST EDA tool generates a Built-In Self-Test (BIST) block able to fully test your convertor. This easily integrates into your design with connections to the clock and ADC.

### Additional Benefits

- Less noisy environment gives faster test
- Suitable for wafer sort *and* final test
- Support for device characterisation
- Patented algorithms minimize BIST area

### ATEEDA

- Experts in analog test
- Already working with major IDMs
- Proven capability in production
- Ask us about LinBIST for DACs too

## Find Out More

To find out more, please contact ATEEDA by e-mail at [sales@ateeda.com](mailto:sales@ateeda.com) or by calling +44 131 272 2754 to arrange a conference call or meeting. Alternatively visit our website at [www.ateeda.com](http://www.ateeda.com)